

Notice of References Cited	Application/Control No. 10/571,464	Applicant(s)/Patent Under Reexamination STEFFL, UDO	
	Examiner RIP A. LEE	Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,114,522	05-1992	Takado et al.	156/245
	B	US-			
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	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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